

Notice of References Cited	Application/Control No. 10/561,624		Applicant(s)/Patent Under Reexamination FABER ET AL.	
	Examiner YUN QIAN		Art Unit 4162	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	D	US-2002/0177685	11-2002	Cook et al.	528/271
*	E	US-5,464,656	11-1995	Verkade, John G.	427/248.1
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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